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## **Support Information**

## **Experimental Section**

Synthesis and crystal growth: All reagents and solved used in the synthesis are commercially available. Pb(CH<sub>3</sub>COO)<sub>2</sub>·3H<sub>2</sub>O (3.79 g, 10 mmol) was dissolved in 40% w/w aqueous HBr solution (30.0 mL) by heating to boiling under constant magnetic stirring to give a yellowish solution. Subsequent addition of formamidiniumacetate (0.512 g, 6.67 mmol) to the hot solution formed red precipitation, which dissolved under stirring to afford a yellow solution. Moreover, n-CH<sub>3</sub>(CH<sub>2</sub>)<sub>3</sub>NH<sub>2</sub> (0.49 g, 6.67 mmol) was added to the above solution to afford a yellow precipitate, which was subsequently dissolved under heating the solution to boiling. As the solution was subjected to a controlled cooling rate of 0.5°C/h to 65°C, the small crystallite formed on the solution surface. When the temperature was further lowered to 55°C, the crystallite grew large enough to begin to slowly sink to the bottom of the container. As we allowed the process to continue until the temperature dropped to 30°C, a bigger single crystal was harvested. The powder X-ray diffraction further verified the purity of 1 (Figure S1). Powder X-ray diffractometry (PXRD) data were recorded on a Mini Flex II Powder X-ray diffractometer.

**Ferroelectric measurements:** The temperature-dependent *P-E* hysteresis loops and *I-E* curves were measured on a ferroelectric analyzer (Radiant Precision Premier II) using the double-wave method. To avoid electric discharge at high electric field, single crystal of 1 was immersed in silicone oil to measure the *P-E* hysteresis loops. The temperature was carefully controlled by an oil bath. Two pairs of electrodes were formed orthogonally with each other on a single crystal of 1 with carbon paste.

**Optical measurements**: The UV absorptions in solid state were measured at room temperature on a PE Lambda 900 UV-Visible spectrophotometer. The fluorescence measurements were performed on an Edinbergh Analytical instrument FLS920. The conoscopic interference pattern was observed using a Nikon Eclipse LV100POL polarizing microscope. The temperature during measurements was controlled at 290 K using a Linkam TS1500 heating stage.

Photoelectric measurements: Photoelectric measurements were performed with a planar electrode configurations. Two symmetric Au electrodes with a defined gap of 200 μm were sputtered on the flat side of a well-polished single crystal. The electrode materials were proven not to have any obvious influence on the photoelectric properties. Before the photoelectric measurements, the sample was poled by a nonpolar electrical plus in field strength range of -20-30 KV/cm. The current vs voltage (*I-V*) and photocurrent vs time (*I-t*) with light on or off (measured at zero bias) were measured using a high precision electrometer (Keithley6517B). A THORLABS 405 nm pigtailed laser diode (LP405-MF300, 200 mW/cm²) was used for visible light illumination. The incident light intensity was measured by light power meter. The transient photoresponse time was measured using a 1 GHz bandwidth oscilloscope (Tektronix MDO3104) under a nanosecond 355 nm laser (pulse width ~2 ns) at zero bias. The temperature during measurements was controlled at 290 K using a Linkam TS1500 heating stage.

Respond time was recorded by the high-speed Tektronix MDO3014 Oscilloscope. Conductivity was tested in the heating mode with range from 300-400 K by using a direct-current two-terminal method. The UV absorptions in solid state were measured at room temperature on a PE Lambda 900 UV-Visible spectrophotometer. The fluorescence measurements were performed on an Edinbergh Analytical instrument FLS920. The responsivity (R) of and the corresponding detectivity (D\*) of the device are calculated from the following equations:

$$\mathsf{R} = (I_{\mathsf{on}} \, \text{-} I_{\mathsf{off}})/P_{\mathsf{in}}$$

$$D^* = R/(2qI_{off}/S)^{1/2}$$

where  $I_{on}$  is the photocurrent,  $I_{off}$  is the dark current,  $P_{in}$  is the incident light power, S is the effective area of light, and q is the electron charge.

## **Figures**

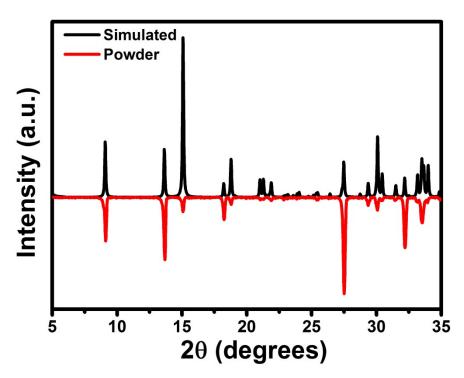
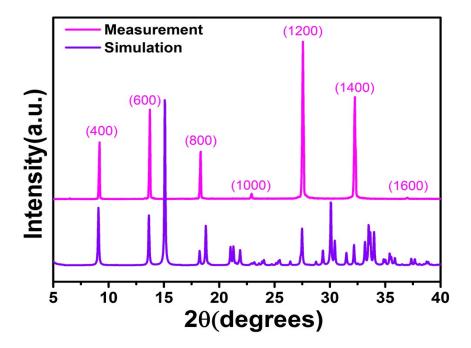


Figure S1. Experimental and simulated PXRD patterns for 1.



**Figure S2.** XRD patterns of the crystallographic facets of **1** showing high crystalline quality. The purple and pink curves indicate simulated and experimental XRD patterns, respectively.

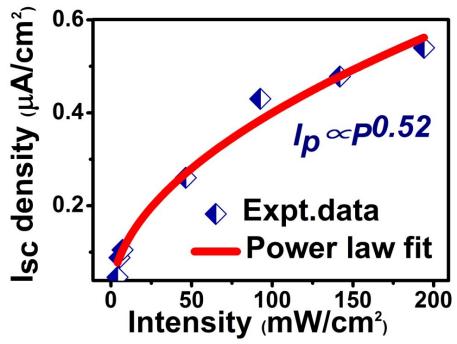


Figure S3.power law fitting of the relation between I<sub>sc</sub> and light intensity.

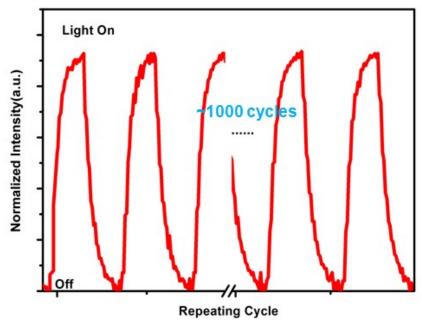
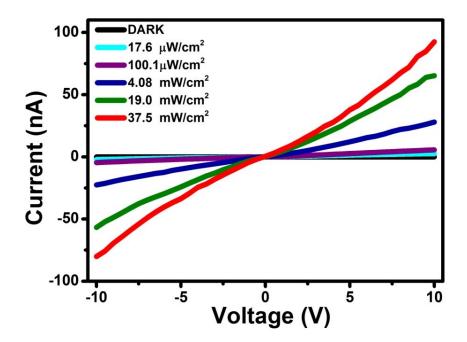
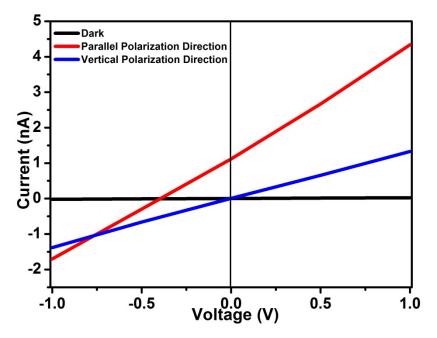


Figure S4. Repetitive switching cycles of photoresponse for 1, showing no obvious attenuation.



**Figure S5.** I–V curves of the **1** single crystal photodetector measured in dark and under illumination with different light intensities. **1** exhibits sizable on/off current ratios (~10<sup>4</sup>).



**Figure S6.** *I-V* traces measured along the polarization revealing a strong photovoltaic behavior. *I-V* traces collected perpendicular to its polarization direction.

Table S1 Basic parameters of semiconductors used in self-powered photodetectors.

Self-powered	V <sub>oc</sub>	I <sub>sc</sub>	Detection Limit	Responsivity	Detectivity	Rise Time	Decay
Photodetectors					(Jones)		Time
WSe <sub>2</sub> /MoS <sub>2</sub> <sup>1</sup>	~0.27 V	~0.22 μA	0.50 μW cm <sup>-1</sup>	44 mA W <sup>-1</sup>	-	-	-
g-C <sub>3</sub> N <sub>4</sub> -PVDF <sup>2</sup>	~2.7 V	-	0.10 mW cm <sup>-1</sup>	1.7 μA W <sup>-1</sup>	-	6.2 s	12.9 s
BiFeO <sub>3</sub> <sup>3</sup>	~0.7 V	-	45 μW cm <sup>-1</sup>	0.66 mA W <sup>-1</sup>	5.13×10 <sup>7</sup>	-	-
BaTiO <sub>3</sub> <sup>4</sup>		~40 nA	3.5 mW cm <sup>-1</sup>	0.45 μA W <sup>-1</sup>	4×10 <sup>5</sup>	-	1.6 s
PZT <sup>5</sup>	~2.85 V	~28.76 nA	15.7 mW cm <sup>-1</sup>	1 V W <sup>-1</sup>	-	2.2 s	22.6 s
Polyaniline/MgZnO <sup>6</sup>	~2.5 V	~0.44 pA	130 μW cm <sup>-1</sup>	160 μA W-1	1.5×10 <sup>11</sup>	4.8 S	5.1 S
ZnO microwire/p-Si films <sup>7</sup>	~2 V	~71 nA	0.58 mW cm <sup>-1</sup>	-	-	<0.3 S	<0.3 S
Present Work	~0.4 V	~2.2 nA	82 nW cm <sup>-1</sup>	0.51mA W <sup>-1</sup>	1.47×10 <sup>12</sup>	220 μs	370 μs

## References

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